

Notice of References Cited	Application/Control No. 10/731,566	Applicant(s)/Patent Under Reexamination VANDLING, GILBERT C.	
	Examiner Vuthe Siek	Art Unit 2825	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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	Q					
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	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Girard et al., "A Trace-Based Method for Delay Fault Diagnosis in Synchronous Sequential Circuits," IEEE, 1995, pages 526-532.
	V	Ranjan et al., "Using Combinational Verification for Sequential Circuits," IEEE, Jan 1999, pp. 1-7.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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